

**Notice of References Cited**

Application/Control No.

10/815,614

Applicant(s)/Patent Under  
Reexamination  
LAPSTUN ET AL.

Examiner

FAN ZHANG

Art Unit

4157

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,818,031 A	10-1998	Endoh, Naoki	235/494
*	B	US-5,834,530 A	11-1998	Ramcke et al.	522/157
*	C	US-6,201,901 B1	03-2001	Zhou et al.	382/306
*	D	US-2002/0067267 A1	06-2002	Kirkham, Richard	340/572.7
*	E	US-2003/0201325 A1	10-2003	Saito, Takahiro	235/462.04
*	F	US-2006/0118631 A1	06-2006	Lubow et al.	235/462.01
*	G	US-7,180,627 B2	02-2007	Moylan et al.	358/1.6
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
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	X					

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